

## 5.10: Rietveld method

---

Method of analyzing powder diffraction data in which the crystal structure is refined by fitting the entire profile of the diffraction pattern to a calculated profile using a least-squares approach. There is no intermediate step of extracting structure factors, and so patterns containing many overlapping Bragg peaks can be analyzed.

---

This page titled [5.10: Rietveld method](#) is shared under a [CC BY 4.0](#) license and was authored, remixed, and/or curated by [Online Dictionary of Crystallography](#) via [source content](#) that was edited to the style and standards of the LibreTexts platform.